

#### **Description**

#### 30V N-CHANNEL ENHANCEMENT MODE POWER MOSFET

#### **Features**

- Device Rating V<sub>DS</sub> = 30V, I<sub>D</sub> = 377A
- $R_{DS(ON)} = 1m\Omega$  (typ.) @  $V_{GS} = 10V$ ,  $I_D = 20A$
- Proprietary High Density Trench Technology
- RoHS Compliant & Halogen-Free

JFG377N30L

#### **Application**

- BMS
- E-Tool
- DC/DC
- POL
- · CPU power

# Package (5) (6) (7) (8) DFN 5\*6-8L

#### Absolute Maximum Ratings Tc=25℃ unless otherwise specified

Symbol	Parameter		Max.	Units
V <sub>DS</sub>	Drain-Source Voltage		30	V
V <sub>G</sub> s	Gate-Source Voltage		± 20	V
ID	Continuous Drain Current, VGS @ 10V note1	T <sub>C</sub> = 25°C	377	А
		T <sub>C</sub> = 100°C	238	Α
I <sub>DM</sub>	Pulsed Drain Current note2		1130	Α
P <sub>D</sub>	Power Dissipation note4	T <sub>C</sub> = 25°C	250	W
	Power Dissipation	T <sub>A</sub> = 25°C	2.5	W
E <sub>AS</sub>	Single Pulsed Avalanche Energy note3	320	mJ	
R <sub>0</sub> JC	Thermal Resistance, Junction to Case note1	0.5	°C/W	
RθJA	Junction to Ambient (mounted on 1 inch square	50	°C/W	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C

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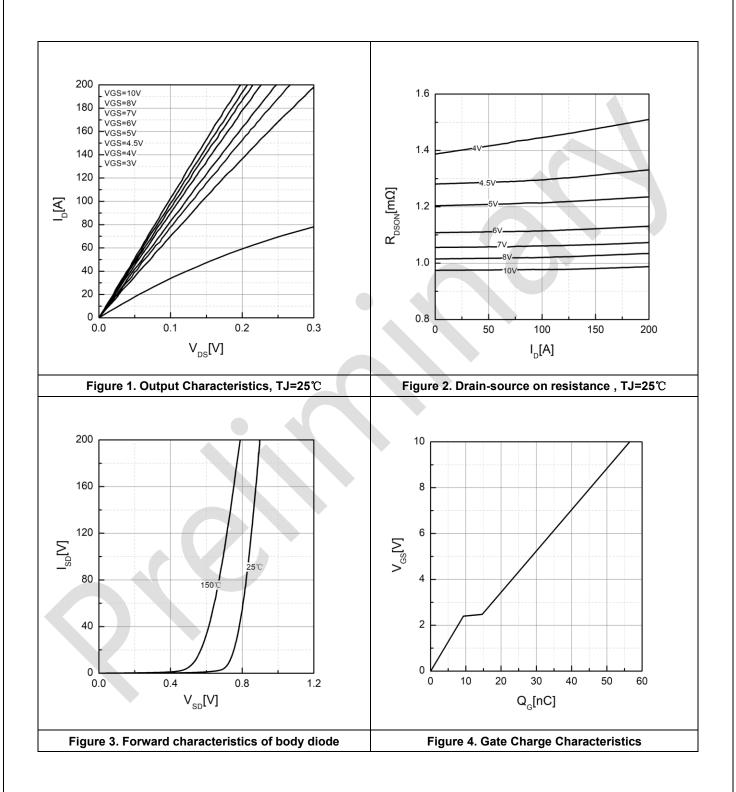
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	cteristic					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V$ , $I_D = 250 \mu A$	30	-	-	V
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =30V,V <sub>GS</sub> = 0V, T <sub>C</sub> = 25°C	-	-	1	μA
		V <sub>DS</sub> =30V,V <sub>GS</sub> = 0V, T <sub>C</sub> = 55°C	-	-	10	μΑ
Igss	Gate-Source Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-100	-	100	nA
On Charac	cteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1	-	2.5	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> =20A	-	1	1.2	mΩ
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 4.5V, I <sub>D</sub> =20A	-	1.3	1.6	mΩ
<b>g</b> FS	Forward Transconductance	V <sub>DS</sub> = 1V, I <sub>D</sub> =20A	1	125	-	S
Dynamic C	Characteristics					
Rg	Gate Resistance		-	1.1	-	Ω
Ciss	Input Capacitance	V 45VV 0V	-	4090	-	pF
Coss	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1MHz$	-	1200	-	pF
Crss	Reverse Transfer Capacitance	1 - IIVITZ	-	83	-	pF
Qg	Total Gate Charge	V 45V I 00A	-	57	-	nC
Qgs	Gate-Source Charge	$V_{DS} = 15V, I_D = 20A,$	-	9.3	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge	V <sub>GS</sub> = 10V	-	5.4	-	nC
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time		_	14	-	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 15V$ , $I_D = 20A$ ,	-	8	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 1\Omega$ , $V_{GS} = 10V$	-	90	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	15	-	ns
Source-Dr	ain Diode Characteristics and Maxim	um Ratings	•			
Is	Maximum Continuous Diode Forward Current note1,5		-	-	208	Α
Іѕм	Maximum Pulsed Diode Forward Current note2,5		-	-	1130	Α
t <sub>rr</sub>	Reverse Recovery Time	T <sub>J</sub> = 25°C, I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	43	-	ns
Qrr	Reverse Recovery Charge	di/dt = 100A/μs	-	43	-	nC
Vsp note2	Source to Drain Diode Forward Voltage	T <sub>J</sub> = 25°C, I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	0.75	-	٧

#### Note

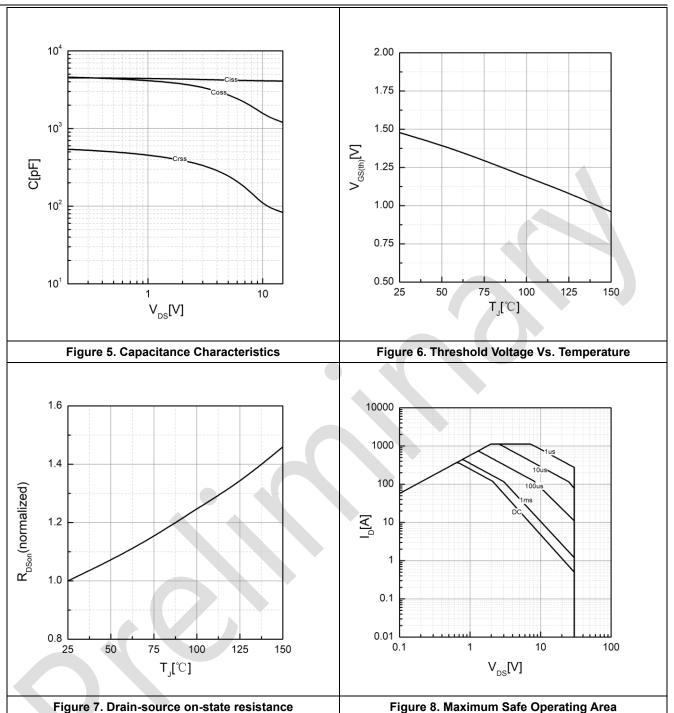
- 1. The data tested by surface mounted on one inch $^2\,$  FR-4 board with 2OZ copper.
- 2.The data tested by pulsed, pulse width  $\,\leq\,$  300us, duty cycle  $\,\leq\,$  2%.
- 3. The EAS data shows Max. rating. The test condition is L=0.1mH, IAS= 80 A.
- 4.The power dissipation is limited by 150°C junction temperature.
- 5.The data is theoretically the same as  $l_D$  and  $l_{DM}$ , in real applications, should be limited by total power dissipation.



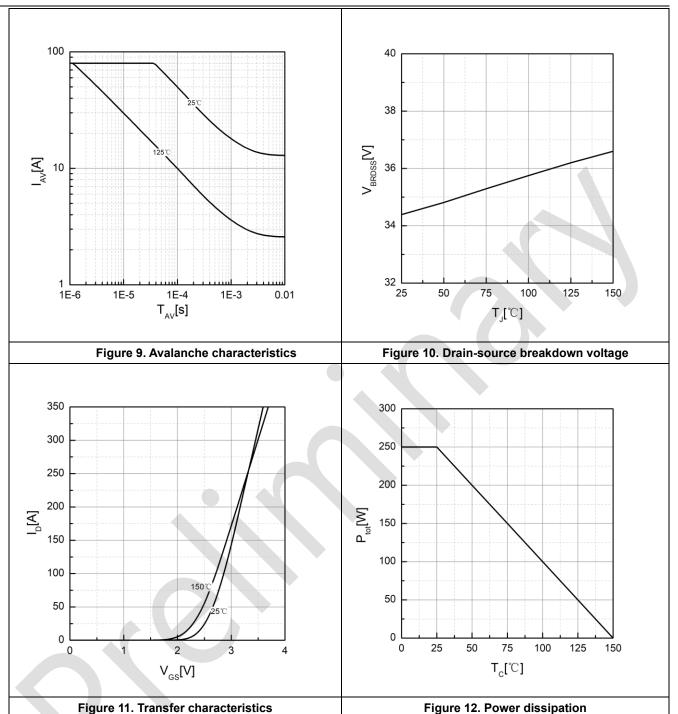
#### **Typical Performance Characteristics**



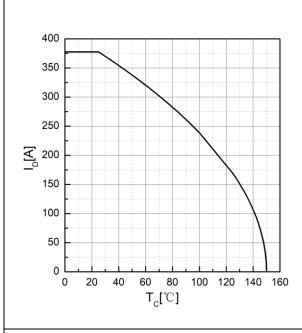












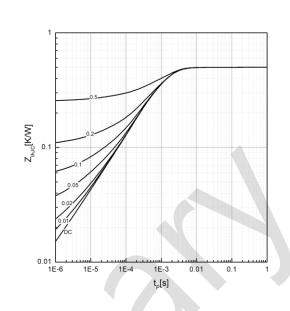


Figure 13. Drain current

Figure 14. Effective Transient Thermal Impedance

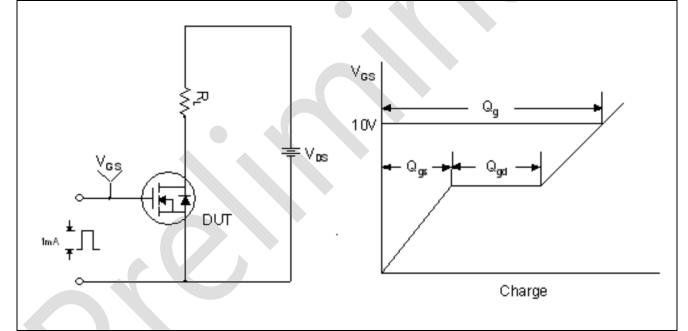


Figure 15. Gate Charge Test Circuit & Waveform



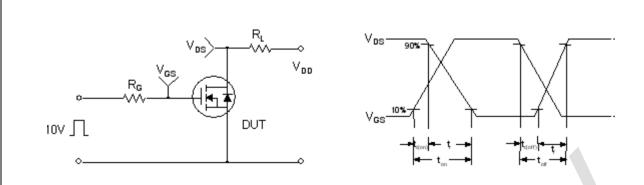


Figure 16. Resistive Switching Test Circuit & Waveforms

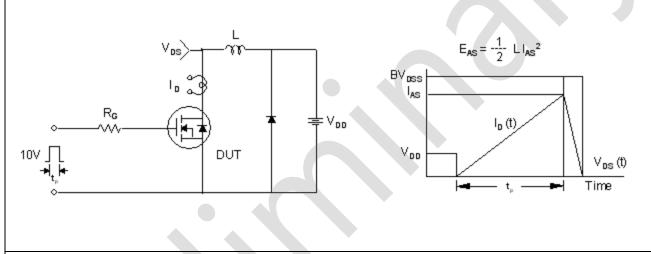
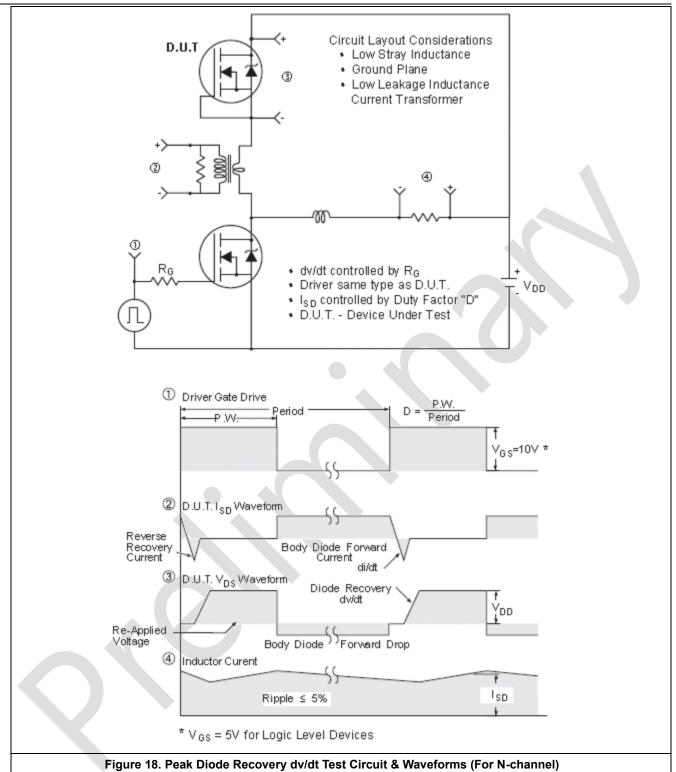
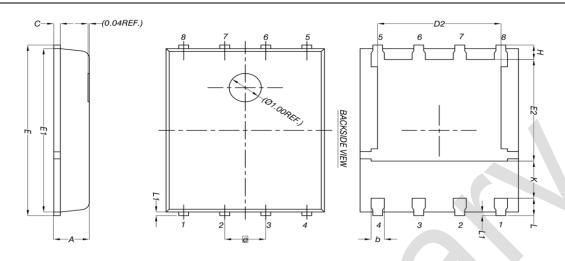


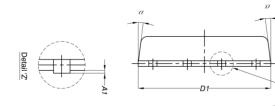
Figure 17. Unclamped Inductive Switching Test Circuit & Waveforms



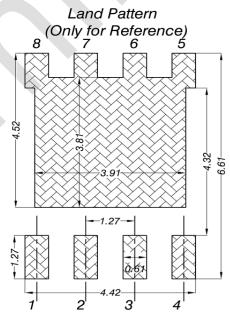


#### Package outline





		411 I IN 4ET	-DC		
DIM.	MILLIMETERS				
Dilvi.	MIN.	NOM.	MAX.		
Α	0.90	1.00	1.10		
A1	0	_	0.05		
b	0.33	0.41	0.51		
С	0.20	0.25	0.30		
D1	4.80	4.90	5.00		
D2	3.61	3.81	3.96		
Ε	5.90	6.00	6.10		
E1	5.70	5.75	5.80		
E2	3.38	3.58	3.78		
е	1.27 BSC				
Н	0.41	0.51	0.61		
K	1.10	-	-		
L	0.51	0.61	0.71		
L1	0.06	0.13	0.20		
α	0°	-	12°		



#### Note:

- 1. All Dimension Are In mm.
- Package Body Sizes Exclude Mold Flash, Protrusion Or Gate Burrs. Mold Flash, Protrusion Or Gate Burrs Shall Not Exceed 0.10 mm Per Side.
- 3. Package Body Sizes Determined At The Outermost Extremes Of The Plastic Body Exclusive Of Mold Flash, Tie Bar, Tie Bar Burrs, Gate Burrs And Interlead Flash, But Including Any Mismatch Between The Top And Bottom Of The Plastic Body.
- 4. The Package Top May Be Smaller Than The Package Bottom.

Figure 19. DFN 5x6 Package outline



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